Form PTO-1449 (Substitute) PATENT AND TRADEMARK OFFICE

Ammey Docket Number Serial/Patent Number LAZE-01011US1 10/684,883

Information Disclosure Statement
BY APPLICANT
(Use several sheets if necessary)

Applicant/Patent Owner
Thomas F. Rust
Filing/Issue Date

10/14/2003

Group Art Unit 2655

			U.S.	PATENTS			
Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
ap	1	4,340,953	07/20/82	Iwamura et al.	369	126	05/07/80
1	2	4,575,822	03/11/86	Quate	365	174	02/15/83
	3	4,829,507	05/09/89	Kazan et al.	369	126	08/15/88
	4	4,831,614	05/16/89	Duerig et al.	369	101	03/13/87
	5_	4,916,688	04/10/90	Foster et al.	369	126	03/31/88
	6	4,945,515	07/31/90	Ooumi et al.	365	174	09/12/88
	7	4,962,480	10/09/90	Ooumi et al.	365	151	09/12/88
	8	4,987,312	01/22/91	Eigler	250	492.3	11/07/89
	9	5,038,322	08/06/91	Van Loenen	365	114	02/03/89
	10	5,043,578	08/27/91	Guethner et al.	250	307	04/05/90
	11	5,051,977	09/24/91	Goldberg	369	126	08/30/89
	12	5,091,880	02/25/92	Isono et al.	365	151 '	· 01/29/90
	13	5,095,479	03/10/92	Harigaya et al.	369	288	08/12/91
	14	5,097,443	03/17/92	Kaneko et al.	365	153	03/28/90
	15	5,144,148	09/01/92	Eigler	250	492.3	08/07/90
	16	5,187,367	02/16/93	Miyazaki et al.	250	306	08/08/91
	17	5,216,631	06/01/93	Sliwa, Jr.	365	174	11/02/90
	18	5,251,200	10/05/93	Hatanaka et al.	369	126	09/11/91
	19	5,260,567	11/09/93	Kuroda et al.	250	227.19	04/08/92
	20	5,262,981	11/16/93	Rabe et al.	365	120	07/01/91
	21	5,265,046	11/23/93	Fuchs et al.	365	151	12/30/91
ap	22	5,289,455	02/22/94	Kuroda et al.	369	126	07/23/91

		MADRIARY	U.S.	PATENTS			
Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
ap	23	5,307,311	04/26/94	Sliwa, Jr.	365	174	02/09/93
1	24	5,323,375	06/21/94	Ihara et al.	369	126	03/09/92
	25	5,335,197	08/02/94	Kaneko et al.	365	153	12/10/91
	26	5,389,475	02/14/95	Yanagisawa et al.	430	019	06/18/92
	27	5,412,597	5/02/95	Miyazaki et al.	365	174	10/15/93
	28	5,446,684	08/29/95	Kaneko et al.	365	046	05/10/94
	29	5,453,970	09/26/95	Rust et al.	369	176	07/13/93
	30	5,471,064	11/28/95	Koyanagi et al.	250	452.2	09/14/93
	31	5,471,458	11/28/95	Oguchi et al.	369	126	09/08/93
	32	5,557,596	09/17/96	Gibson et al.	369	101	07/12/95
	33	5,606,162	02/25/97	Buser et al.	250	306	07/01/96
	34	5,751,685	05/12/98	Yi	369	126	05/10/96
	35	5,778,134	07/07/98	Sakai et al.	386	046	09/03/96
	36	5,804,710	09/08/98	Mamin et al.	073	105	06/05/97
	37	5,808,973	09/15/98	Tanaka	369	14	09/06/96
	38	5,822,285	10/13/98	Rugar et al.	369	44.26	03/31/97
	39	5,835,477	11/10/98	Binning et al.	369	126	07/10/96
	40	5,848,077	12/08/98	Kamae et al.	371	053	12/08/95
	41	5,856,967	01/05/99	Mamin et al.	369	126	08/27/97
	42	5,929,438	07/27/99	Suzuki et al.	250	306	01/16/97
	43	5,953,306	09/14/99	Yi	369	126	04/25/97
	44	6,001,519	12/14/99	Yang et al.	430	020	07/02/98
	45	6,027,951	02/22/2000	MacDonald et al.	438	020	08/18/98
	46	6,038,916	03/21/00	Cleveland et al.	073	105	07/22/97
	47	6,196,061	03/06/2001	Adderton et al.	073	105	11/05/98
	48	6,275,410 B1	08/14/2001	Morford	365	151	11/09/2000
ap	49	6,339,217	01/15/2002	Kley	250	216	07/28/95

		TAMBUM CE	U.S	S. PATENTS					=	
Examiner Initial		Patent Number	Issue Date	First	First Named Inve		Class	Subclass	Filing Da	ate
ap.	50	6,507,552 B2	01/14/2003	Gibson			369	126	12/01/20	000
a	51	6,522,566 B2	02/18/2003	Carter			365	118	12/01/20	000
ap	52	6,542,400 B2	04/01/2003	Chen et a	1.		365	151	03/27/20	001
7										
			U.S. PATE	NT PUBLIC	ATION	S				
Examiner Initial		Patent Application Public	ation Number	Publication	Date	Applicant				
ap	53	US 2002/0110074 A1	•	08/15/2002		Gibson				
	54	US 2002/0135917 A1		09/26/2002		Davidson				
	55	US 2003/0007443 A1		01/09/2003		Nickel				
	56	US 2003/0081532 A1		05/01/2003		Gibson				
	57	US 2003/0185139 A1		10/02/2003		Ives				
ap	58	US 2003/0189200 A1		10/09/2003		Lee et al.			<u></u>	
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PENDING U.S. PATENT APPLICATIONS										
Examiner Initial		Application Number	F	Filing Date		First Name	d Inventor	r	Petition Expuns Yes 1	ge?
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			FOREIGN PA	TENT DOCUMENTS			•	
Examiner Initial		Document Number	Publication Date	Country	Class	Subclass	lai	ans- tion No
ap	59	WO 96/11472	04/18/96	PCT				
	60	JP3295043	12/26/91	JAPAN			x	
	61	JP3295044	12/26/91	JAPAN			x	
ap	62	JP4159636	06/02/92	JAPAN			x	
1								

	ОТНІ	ER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)
ap	63	BO HONG, Exploring the Usage of MEMS-based Storage as Metadata Storage and Disk Cache in Storage Hierarchy, Storage Systems Research Center, Jack Baskin School of Engineering, University of California at Santa Cruz http://www.cse.ucsc.edu/~hongbo/publications/mems-metadata.pdf
	64	SUMIO HOSAKA, HAJIME KOYANAGI AND ATSUSHI KIKUKAWA, Nanometer Recording on Graphite and SI Substrate Using an Atomic Force Microscope in Air, Japan Journal of Applied Physics, Volume 32 (1993) pp. L464-467, Part 2, No. 3B, March 15, 1993, Central Research Laboratory, Hitachi Limited, Kokubunji, Tokyo 185
	65	ATSUSHI KIKUKAWA, SUMIO HOSAKA, YUKIO HONDA' and RYO IMURA, Phase-Controlled Scanning Force Microscope, Japanese Journal of Applied Physics, Volume 33 (1994) pp. L1286-L1288, Part 2, No. 9A, September 1, 1994, Advanced Research Laboratory, Hitachi Limited, 1-280 Higashi-koigakubo, Kokubunji-shi, Tokyo 185, 'Central Research Laboratory, Hitachi Limited, 1-280 Higashi-koigakubo Kokubunji-shi, Tokyo 185
	66	WILLIAM P. KING, DANIEL A. FLETCHER and Y. SUNGTAEK JU, Nanometer-Scale Thermal Processing for Advanced Manufacturing (YIP '96), Office of Naval Research Annual Grant Report, First Annual Report: May 1, 1996 - April 30, 1997, pp. 1 - 8
	67	T. C. REILEY, T.R. ALBRECHT, D. W. ALBRECHT, K. KUROKI and M. AOYAGI, A Micro Hard Disk Drive, I.B. M Almaden Research Center, I.B.M. Storage System Division, Electrochemical Society Proceeding, Volume 98-20, pp. 10 - 18
	68	SEIJI HEIKI, YASUO WADA and TOMIHIRO HASHIZUME, Correlation Between Tip-Apex Shape and Surface Modification by Scanning Tunneling Microscopy, Journal of Applied Physics, Vol. 86, No. 8, pp. 4220 - 4224
	69	MICHAEL BROOKS, Hole in One, New Scientist, March 27, 1999, pp. 46 - 48
	70	H. JONATHON MAMIN, ROBERT P. RIED, BRUCE D. TERRIS and DANIEL RUGAR, High-Density Data Storage Based on the Atomic Force Microscope, Proceeding of the IEEE, Volume 87, No. 6, June 1999, pp. 1014 - 1027
	71	STEVEN W. SCHLOSSER, JOHN LINWOOD GRIFFIN, DAVID F. NAGLE, AND GREGORY R. GANER, Filling the Memory Access Gap: A Case for On-Chip Magnetic Storage, School of Computer Science, Camegie Mellon University, November 1999
	72	STEVEN W. SCHLOSSER, JOHN LINWOOD GRIFFIN, DAVID F. NAGLE and GREGORY R. GANGER, Carnegie Melton University, Designing Computer Systems with MEMS-Based Storage, 9th International Conference on Architectural Support for Programming Languages and Operating Systems, 2000
	.73	S. HOSAKA, K. ETOH, A. KIKUKAWA AND H. KOYANAGI, Megahertz Silicon Atomic Force Microscopy (AFM) Catilever and High-Speed Readout in AFM-Based Recording, Journal of Vacuum Science Technology, Vol 18, No. 1, Januarary/February 2000, pp. 94 - 99
	74	ROBERT P. RIED, Air-Bearing Sliders and Plane-Plane-Concave Tips for Atomic Force Microscope Cantilevers, Journal of Microelectromechanical Systems, Volume 9, No. 1, March 2000, pp. 52 - 57
	75	L. RICHARD CARLEY, GREGORY R. GANGER and DAVID F. NAGLE, Mems-Based Integrated-Circuit Mass- Storage Systems, Communications of the ACM, Volume 43, No., 11, November 2000, pp. 73 - 80
ap	76	P. VETTIGER, M. DESPONT, U. DRECHSLER, U. DURIG, W. HABERLE, M. I. LUTWYCHE, H.E. ROTHUIZEN, R. STUTZ, R. WIDMER AND G. K. BINNIG, The "Millipede" - More than one thousand tips for future AFM data storage, I.B.M. J. Res. Develop., Volume 44, No. 3, May 2000, pp. 323 - 340



	OTH	R BUTTE (Include author (if any), title, publisher and place of publication, date and pertinent pages)
ap	77	R. B. ZMOOD, L. QIN, D. K. SOOD, T. VINAY and D. MEYRICK, School of Electrical and Computer System Engineering, Royal Melbourne Institute of Technology, Melbourne, Victoria 3000, Australia, Magnetic MEMS Used in Smart Structures Which Exploit Magnetic Materials Properties, Smart Structures and Devices, Proceeding of the SPIE, Volume 4235, 2001, pp. 173 - 187
	78	MICHAEL GROSS, Small is Great!, New Scientist, July 14, 2001, pp. 1 - 4
·	79	G. CHERUBINI, T. ANTONAKOPOULOS, P. BACHTOLD, G. K. BINNIG, M. DESPONT, U. DRECHSLER, A. DHOLAKIA, U. DURIG, E. ELEFTHERIOU, B. GOTSMANN, W. HABERLE, M. A. LANTZ, T. LOELIGER, H. POZIDIS, H. E. ROTHUIZEN, R. STUTZ AND P. VETTIGER, I.B.M. Research, Zurich Research Laboratory, The Millipede, a Very Dense, Highly Parallel Scanning-Probe Data-Storage System, ESSCIRC 2002, pp. 121 - 125
	80	E. ELEFTHERIOU, G. CHERUBINI, H. POZIDIS, H. E. ROTHUIZEN AND P. VETTIGER, Millipede - a MEMS-Based Scanning-Probe Data-Storage System, APMRC 2002, pp. 1 - 8
	81	SATOSHI KAWAMURA, Electronics Device Division, Hitachi Maxell, Limited, Coil on Chip RFID System by Super EF2 Technology, Nippon Oyo Jiki Gakkal Kenkyukal Shiryo, Vol. 123, pp. 21 - 25
	82	Molecular Chip Patent, Poptronics, Vol. 3, No. 5, May 2002, pp. 11 - 12
	83	KENNETH J. KORANE, A King-Size Future for Nanosize Machines, Machine Design Vol 74, No. 18, September 19, 2002, pp. 88 - 94
	84	PETER VETTIGER AND GERD BINNIG, The Nanodrive Project: Inventing a Nanotechnology Device for Mass Production and Consumer Use is Trickier than it Sounds, Scientific American, Vol. 288, No. 1, 2002, pp. 47 - 53
	85	MUSTAFA UYSAL, ARIF MERCHANT, GUILLERMO A. ALVAREZ, Hewlett Packard Laboratories, Using MEMs-Based Storage in Disk Arrays, Proceedings of FAST '03: 2" USENIX Conference on File and Storage Technologies, USENIX Association, pp. 89 - 101
	86	KIYOSHI, T., ET AL., "Switching and memory phenomenon in Langmuir-Blodgett film using a scanning tunneling microscope," Canon, Inc., IEIC Technical Report (1994), Vol. 93, No. 524 (OME93 54-59), pp. 7012, Fig 6, Ref. 15.
	87	KIYOSHI T. ET AL., Application and Progress in the Scanning Probe Microscopy, High Density Information Storage Using Langmuir-Blodgett Film and Atomic Force Microscopy," Canon, Inc., Journal of the Surface Science Society of Japan (1997), Vol. 18, No. 4, pp. 213-218, Fig. 7, Ref. 14.
	88	KADO, H. and TOHDA, T., "Nanometer-scale recording on chalcogenide films with an atomic force microscope," Appl. Phys./ Lett., Vol. 66, No. 22, 29 May 1995, pp. 2961-2962.
	89	YANO, K., ET AL., "Nanometer scale conductance change in a Langmuir-Blodgett film with the atomic force microscope," Appl. Phys. Lett., Vol. 68, Vol. 2, 8 January 1996, pp. 188-190.
	90	YANO, K. and IKEDA, T., "Stable bit formation in polyimide Langmuir-Blodgett film using an atomic force microscope," Appl. Phys. Lett., Vol. 80, Vol. 6, 11 February 2002, pp. 1067-1069.
	91	BARRETT, R.C. and QUATE, C.F., "Large-scale charge storage by scanning capacitance microscopy," Ultramicroscopy 42-44 (1992) pp. 262-267.
	92	GARDNER, E., "AFM Fabricates a Tiny Transistor," Science, Vol. 266, 28 October 1994, p. 543.
ap	93	HAGAN, H.P., et al., "Temporal behaviour of nanofeatures on Au," Ultramicroscopy, 42-44 (1992), pp. 587-593.
. I		

	отн	R DOCK MEANS (Include author (if any), title, publisher and place of publication, date and pertinent pages)
ap	94	MAJUMDAR, A., ET AL., "Nanometer-scale lithography using the atomic force microscope," Appl. Phys. Lett., Vol. 61, No. 19, 9 November 1992, pp. 2293-2295.
	95	MAMIN, H.J. and RUGER, D., "Thermomechanical writing with an atomic force microscope tip," App. Phys. Lett., Vol. 61, No. 8, 24 August 1992, pp. 1003-1005.
	96	MAMIN, H.J., ET AL., "High Density data storage using proximal probe techniques," The IBM Journal of Research and Development, Vol. 39, No. 6, November 1995, pp. 681-699.
	97	MANALIS, S., ET AL., "Submicron studies of recording media using thin-film magnetic scanning probes," Applied Physics Letters, Vol. 66, No. 19, 8 May 1995, pp. 2585-2587.
	98	TERRIS, B.D., ET AL., "Atomic force microscope-base data storage: track servo and wear study," Applied Physics A Vol. 66, pp. S809-S813 (1998), (IBM Almaden Research Center, presented STM 97).
	99	UESUGI, K. and YAO, T., "Nanometer-scale fabrication on graphite surfaces by scanning tunneling microscopy," Ultramicroscopy, 42-44 (1992), pp. 1443-1445.
	100	PCT Written Opinion mailed December 18, 2000, International Application No. PCT/US99/30326, filed December 20, 1999
	101	T.C. SHEN ET AL; Ion irradiation effects on graphite with the scanning tunneling microscope; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1376-1379
	102	U. STAUFER ET AL; Tailoring nanostructures with a scanning tunneling microscope; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1389-1393
	103	H.J. MAMIN; Gold deposition from a scanning tunneling microscope tip;, et al.; J.Vac.Sci. Technol B9(2), Mar/Apr 1991; pp.1398-1402
	104	J.A. DAGATA, ET AL. Pattern generation on semiconductor surfaces by a scanning tunneling microscope operating in air;; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1384-1388
	105	T.R. ALBRECHT, ET AL. Nanometer-scale hole formation on graphite using a scanning tunneling microscope;; Appl.Phys.Lett., Vol.55, No.17, 23 October 1989; pp.1727-1729
ap	106	M.AONO; Has Japan Begun to Move Toward Atomic Level Material Processing?; Science, Vol. 258; 23 October 1992
J		
Examin	ner (Cuk Theory Date Considered 1/14/05
*EXAMIN	ER: Ini	tial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in ot considered. Include copy of this form with next communication to applicant.
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PE	In Information Disclosure Statement			Applicant/Parent Owner Thomas F. Rust						
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Examiner Initial		Patent Number	lssue D	ate	First	Named In	ventor	Class	Subclass	Filing Date
ap	1	5,196,701	03/23/19	993	Foster et	al.		250	306	07/31/1991
	2	5,537,372	07/16/19	996	Albrecht	et al.		369	043	11/24/1993
	3	5,561,300	10/01/19	996	Wada et a	ıl.	·-· -	250	492.2	12/22/1992
	4	5,679,952	10/21/19	997	Lutwyche	et al.		250	306	05/19/1995
	5	5,801,472	09/01/19	09/01/1998 V		ada et al.		310	309	08/13/1996
	6	5,856,967	01/05/19	999	Mamin et	al.		369	126	08/27/1997
	7	6,084,849	07/04/20	000	Durig et a	ıl.		369	126	05/20/1996
	8	6,366,340	04/02/20	002	Ishibashi	et al.		355	069	06/05/1998
	9	6,369,400 B2	04/09/2	002	Наевете	et al.		250	548	10/06/1999
ap	10	6,647,766 B2	11/18/20	003	Despont	et al.	•	073	105	12/20/2000
			U.S. PA	TENT	PUBLICA	ATION	s	<u> </u>		
			<u> </u>					<u>.</u>		
Examiner Initial		Patent Application Publi	cation Numbe	er	Publication	Date		A	pplicant	
ap	11	2002/0101573 A1		08	3/01/2002	01/2002 Ishibashi et al.				
1									<u></u>	
	,·-	. P]	ENDING U	J.S. PA	TENT AP	PLICA'	TIONS			
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	<u>,</u>	Aren contra	FOREIGN PA	TENT DOCUMENTS			
Examiner Initial	6.00	Document Number	Publication Date	Country	Class	Subclass	Trans- lation Yes No
ap	12	EP 0 788 149 A1	06/08/1997	EPO	H01L	21/3205	
ap	13	WO 02/37488 A1	05/10/2002	PCT	GIIB	9/00	
ap	14	WO 97/05610	02/13/1997	PCT	GIIB	9/00	

OTH	IER DOCUMENTS (Include author	r (if any), title, publisher and place of p	publication, date and pertinent pages)
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PTO/SB/08A (08-03) Approved for use through 07/31/2006. OMB 0651-0031

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known						
Application Number	10/684,883					
Filing Date	10/14/2003					
First Named Inventor	Thomas F. Rust					
Art Unit	2824					
Examiner Name	Phung, Anh K.					
Attorney Docket Number	LAZE-01011US1					

			U. S. PATENT		
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (f brown)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
GD.		US- 4,340,953	07-1982	lwamura et al.	369/126
7,		^{US-} 4,831,614	05-1989	Duerig et al.	369/101
		US- 4,916,002	04-1990	Carver, Thomas E.	428/139
		^{US-} 4,943,719	07-1990	Akamine et al.	250/306
		^{US-} 4,968,585	11-1990	Albrecht et al.	430/320
		^{US-} 5,095,479	03-1992	Harigaya et al.	369/288
		^{US-} 5,329,122	07-1994	Sakai et al.	250/306
		^{US-} 5,412,597	05-1995	Miyazaki et al.	369/126
		^{US-} 5,471,064	11-1995	Koyanagi et al.	250/492.2
		^{US-} 5,606,162	02-1997	Buser et al.	250/306
		^{US-} 5,804,710	09-1998	Mamin et al.	73/105
		^{US-} 5,808,973	09-1998	Tanaka, Yoichiro	369/126
		^{US-} 5,929,438	07-1999	Suzuki et al.	250/306
		^{US-} 5,935,339	08-1999	Henderson et al.	134/1
		^{US-} 6,001,519	12-1999	Yang et al.	250/306
	Ì	^{US-} 6,027,951	02-2000	MacDonald et al.	438/20
		^{US-} 6,196,061	03-2001	Adderton et al.	250/492.2
		^{US-} 6,249,747	06-2001	Binnig et al.	369/126
an		^{US-} 6,339,217	01-2002	Kley, Victor B.	250/216

-/		FORE	IGN PATENT DOCU	MENTS		
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	
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This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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